

Picking the Right TMD is the Key to Controlling Heat In a Phase Change Superlattice

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Introduction

Although phase change materials, such as GST, generally boast a low thermal conductivity in the amorphous phase, this often changes drastically upon crystallization. This is problematic as a loss of energy, due to heat diffusion into the surroundings, contributes to the high energy consumption of this novel type of memory. One promising way of tackling this high contrast in thermal conductivity, is by incorporating the phase change material into a superlattice. For example, interlacing Sb₂Te₃ with thin layers of TiTe₂ has proven to reduce the thermal conductivity, even in the crystalline phase. This in turn contributes to the superb performance, demonstrated by these structures [1]. TiTe₂ has, by itself, a relatively high thermal conductivity, which begs the question if TiTe₂ is the best choice for this application. In the search for new materials to be used in these superlattices, three alternative transition-metal ditellurides are presented: WTe₂, VTe₂ and ZrTe₂.

Methods

To create the different metal-ditelluride films and superlattices, magnetron sputtering is applied from elementary pure targets. Magnetrons are energized in a planetary geometry, while the substrate passes underneath. Through this way, the stoichiometry of the deposited layer can be controlled and highly crystalline materials can be achieved after anneal [2]. An automated shutter system is used to create the superlattice of Sb₂Te₃ and the different MTe₂ candidates. Thermal conductivity is measured using time-domain thermoreflectance (TDTR), a laser-based pump probe technique that can directly probes the thermal response of a system of thin-films. Samples are covered with a 80nm Ru transducer. The transducer turns the power of the laser into heat (pump), while its reflectivity acts as an indicator of the surface temperature (probe) [3].

Structural Characterization

The three materials show little to no crystallinity right after deposition. While both VTe₂ and ZrTe₂ crystallize upon anneal, we were not able to crystallize WTe₂. For this reason, we focus solely on the first two materials. After an anneal to 300°C, both materials crystallize into a highly textured CdI₂ structure with 00L planes parallel to the Si substrate. This can be seen in the rocking curve and XRD data shown in Fig. 1. A sample containing 80nm VTe₂ is shown on the left, the right side shows a 5nm Sb₂Te₃ / 3nm ZrTe₂ superlattice. Peaks of both materials are present in the superlattice, next to satellite peaks that are a result of the superlattice structure.

Thermal Conductivity Results

A room-temperature study of all three candidate materials is first performed. Creating a thickness series allows us to extrapolate-out interface resistances and reveal the intrinsic thermal conductivity of the materials. An example of this analysis for ZrTe₂ is shown on the left of Fig. 2. On the right, a comparison is made between the three candidate materials, TiTe₂ and Sb₂Te₃. All three candidates have very little contrast between the two states, with ZrTe₂ displaying the lowest thermal conductivity. To characterize ZrTe₂ even further, an in situ study is performed, results can be seen in Fig. 3. After crystallization, the thermal conductivity for ZrTe₂ stays under that of Sb₂Te₃, which is exactly what is wanted for a good superlattice. A 5nm Sb₂Te₃ / 3nm ZrTe₂ superlattice displays a consistently low thermal conductivity all the way up to 450°C..

Conclusions

Both VTe₂ and ZrTe₂ make promising candidates for use in PCM superlattices due to their high crystalline quality, thermal stability and consistently low thermal conductivity contrast. On top of this, ZrTe₂ and its superlattice demonstrate a low thermal conductivity, even at high temperatures, making it a prime candidate for further investigations.

References

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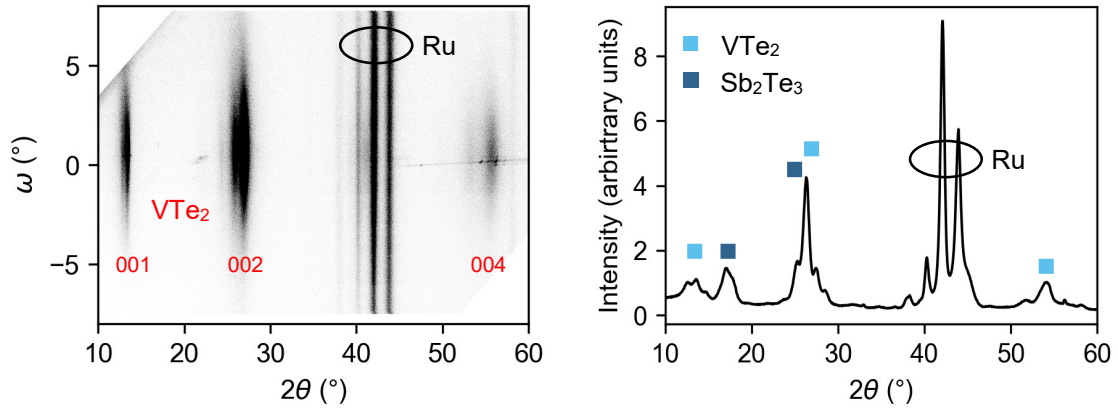


Figure 1. (left) XRD and rocking curve data show the high quality and structure of sputtered VTe_2 after an anneal to 450°C . The 80nm ruthenium transducer layer is also visible. (right) XRD data for the $\text{VTe}_2/\text{Sb}_2\text{Te}_3$ superlattice shows that both phases are present in the superlattice. The visible satellite peaks indicate an ordered superlattice structure.

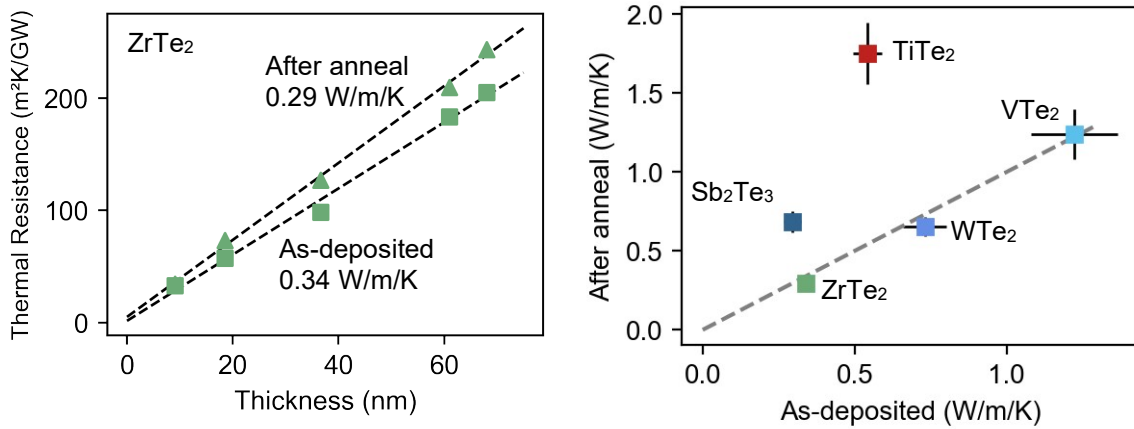


Figure 2. (left) Creating a thickness series of the same material, allows us to calculate the intrinsic thermal conductivity of the materials. Shown is the data for ZrTe_2 between 10 and 80 nm. (right) All three materials show a very low contrast in thermal conductivity. They lie close to dashed line, which signifies zero contrast.

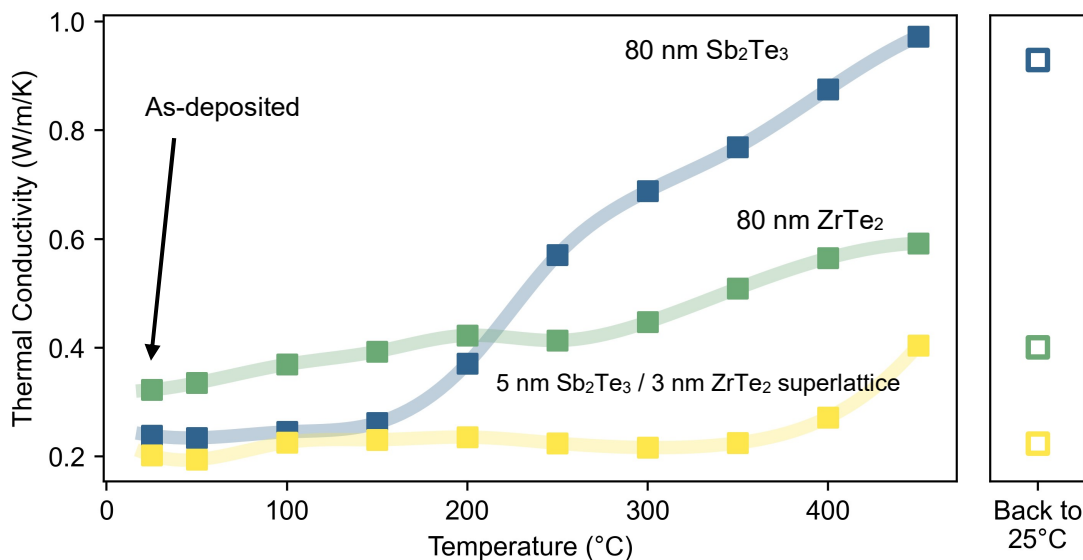


Figure 5 At high temperatures the thermal conductivity of ZrTe_2 only increases slightly, while that of Sb_2Te_3 increases drastically. The superlattice with 16 periods of these materials performs very well in the studied temperature range.